Application/Control No. Applicant(s)/Patent Under Reexamination BERENS ET AL. Examiner JYOTHSNA A. VENKAT Ph. D Applicant(s)/Patent Under Reexamination BERENS ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,939,089	02-1976	Matsumoto et al.	252/79.4
	В	US-5,151,425	09-1992	Clark, LeaLand L.	514/263.4
	С	US-			
	D	US-			
	E	US-		·	
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	к	US-			·
	L	US-		·	
	М	US-			

FOREIGN PATENT DOCUMENTS

TOTAL							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N	EP 1000 622	05-2000	EP	HIRASAWA et al.	*****	
	0						
	Р				•		
	Q						
	R						
	s	·					
	T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP ABSTRACT 03-133920 (7/91)
	· V	CHEMICAL ABSTRACT 87: 95916 (1977)
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.